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25X1



Monthly Report

PAR 211

29 Oct 65

SUBJECT: Microdensitometer Study of Effects of Processing

TASK/PROBLEM

1. Collect and study microdensitometric data from mission materials in an attempt to determine the effect of film emulsions, processing, and printing on the characteristics of image edges. Also, attempt to determine the true location of image edges for mensuration purposes.

DISCUSSION

2. The final report, PAR 211, Microdensitometer Study of Effects of Processing, (AL-45-700092-), dated 20 August 1965, was transmitted to the customer on 28 October 1965.

PLANNED ACTIVITY

3. Publication of the final report constitutes project termination.

Declass Review by NGA.

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SUMMARY

Image structure data have been collected on three typical aerial negative film types: 4400, 4401, 4404. Seven processings were used for these materials. These were the standard Trenton three-condition processes and four sensitometric processings: two with special purpose developers designed to give high sharpness and two with special purpose developers expected to give low graininess.

It was found that the Trenton processing produced higher acutance and better low contrast resolving power than did any of the special formulations for the 4400 and 4404 films. The special formulations showed lower granularity than the Trenton processing for all three emulsions. The state-of-the-art appears to be that optimum sharpness and optimum granularity are mutually exclusive, and that a practical mission developer should be selected as a best compromise of sharpness and granularity in combination with some other properties such as increased emulsion speed or exposure control through processing.

Comparative evaluations using simulated photography, printing tests, and complete modulation transfer measurements were planned, but could not be scheduled before project termination. Study was made of the customer's mensuration problem, and recommendations for further work are included in this report.

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INTRODUCTION

2. An ideal photoreconnaissance system should, among other things, completely resolve all ground detail and permit accurate determination of the size of all ground objects. That photographic systems always depart from this ideal is well known. It was the intention of this project to study the relationship of some of the distortions or non-linearities of the photographic system with changes in developer composition. It was hoped that a knowledge of the causes of these distortions might point the way toward methods for reducing the degradations or might alternatively indicate ways to compensate for the degradations.

3. It was proposed that several high quality negative films would be processed with standard and special purpose developers, and then be evaluated for acutance, granularity, resolving power, and modulation transfer function. Prints of simulated aerial scenes would be made from these negative/processing combinations permitting subjective evaluation for comparison with the objective measurements. As a separate part of the project, it was proposed that a visit be made to the customer's shop to see his methods of linear mensuration, to form a background for studies in methods of improving mensuration at or near the limit of resolution.

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4. Termination of the work phase of this project has made it impossible to realize all of the proposed goals.

DISCUSSION

5. Film Selection: The proposal called for the use of three photographic films in this project. These were:

- 25X1
- a. Panatomic-X Aerial Film (Estar Thin Base), Type 4400.*
 - b. Plus-X Aerial Film (Estar Thin Base), Type 4401.*
 - c. High Definition Aerial Film (Estar Thin Base), Type 4404.*

These films are in common usage in aerial reconnaissance at low to very high altitudes and are representative of the current state-of-the-art in medium to slow speed films (exposure index of 64 to 1.6). The inclusion of other film types was not believed necessary at the start of the project. That assumption appears to be correct. Any further work along the lines of this study should continue investigation of the image structure of these films, rather than add more film types to the investigation.

6. Processing: Of the almost unlimited number of developer formulations available, the choice for investigation was restricted to two standard spray formulations as used in Trenton Primary, Trenton Intermediate, and Trenton Full processing, and four special purpose formulations: two producing

* These films are now identified as Types 3400, 3401, and 3404. The 3000 designation identifies the base and base thickness.

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high sharpness and two yielding low graininess. The latter four were selected from the nine studied by Altman and Henn (see Attachment 1), in which a systematic study was made of the relationship of image structure characteristics with variation in the silver solvent concentration (leading to reduced graininess) and variation in the developing agent concentration (leading to increased sharpness).

a. Trenton Process

(1) Processing conditions for these three films in the Trenton spray processor were established prior to the start of this project. This processing was known to give processing contrasts (gammas) of approximately 2.0, emulsion speeds faster than the normal ratings for these films, and good control of the emulsion speed to compensate for exposure deficiencies. The image quality of these films processed by Trenton three-condition methods was believed to be good, but the comparison with special purpose formulations was not known.

(2) Table 1 shows the developers, times, and the temperatures used in Trenton processing. Also included is the processing contrast (gamma) and the aerial speed index* calculated for each film/processing combination.

$$* \text{ Aerial Speed Index } = \frac{1}{2 \times E}$$

where E is the exposure in meter-candle-seconds at a point in the toe region of the negative film curve relating density to log of exposure (H & D curve), at which the slope is 0.6 of the straight line portion (gamma).

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Table 1
DEVELOPMENT CONDITIONS FOR TRENTON PROCESS

Film	Condition	First Developer*			Second Developer*			Gamma	Aerial Speed Index (at 0.6 Gamma)
		Type	Time	Temp. °F	Type	Time	Temp. °F		
4400	Primary	D-19	1'55"	70	- - -	- - -	- - -	1.84	9.6
	Intermediate	D-19	1'55"	70	MX-579	28"	80	2.18	13.2
	Full	D-19	1'55"	70	MX-579	1'38"	80	2.26	18.2
4401	Primary	MX-576	2'	70	- - -	- - -	- - -	1.77	39.0
	Intermediate	MX-576	2'	70	MX-579	20"	80	2.24	42.5
	Full	MX-576	2'	70	MX-579	2'12"	80	2.26	55.0
4404	Primary	MX-574	2'15"	74	MX-577	- - -	- - -	1.98	1.82
	Intermediate	MX-574	2'15"	74	MX-577	25"	67	2.18	2.29
	Full	MX-574	2'15"	74	MX-577	1'16"	67	2.02	3.46

* Formulas for Developers are proprietary except for D-19, which is given below for a 1 liter mix:

Chemical	Amount
Water	300 milliliters
Calgon	0.5 grams
Elon	2.0 grams
Sodium Sulfite	90.0 grams
Hydroquinone	8.0 grams
Sodium Carbonate (anhydrous)	43.9 grams
Potassium Bromide	5.0 grams

Water to 1 Liter

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b. Special Processing

(1) All of the developer formulas given in the Altman and Henn article (Attachment 1) were tried in a preliminary screening. Of the eight possible formulations, two, AH-3 and AH-4 were selected to represent special purpose, fine grain developers, and two, AH-15 and AH-18 were picked for the high sharpness comparisons. All special processing of the 4400, 4401, and 4404 films for image structure testing was conducted in the Kodak Small Capacity Sensitometric Processor (see Figure 1). The preliminary screening showed that it would not be possible to obtain the gamma of 2.0 achieved in the Trenton process with these formulations. It was therefore decided to adjust the agitation rate, times, and temperature to levels that would give a gamma of 0.85 ± 0.10 . While processing was consistent from batch to batch, it was not possible to stay within the tolerance. Adjustment of the chemical formulas was a possibility but this approach was discarded in favor of staying with published formulations. It is believed that the first order affects of gamma change on image structure characteristics are small; and that adjustments could be made in the tone reproduction of the aerial simulations to compensate for the variation in the gammas of the special purpose developer series.

(2) The resultant gammas and emulsion speeds produced in the special processing series are given in Table 2.

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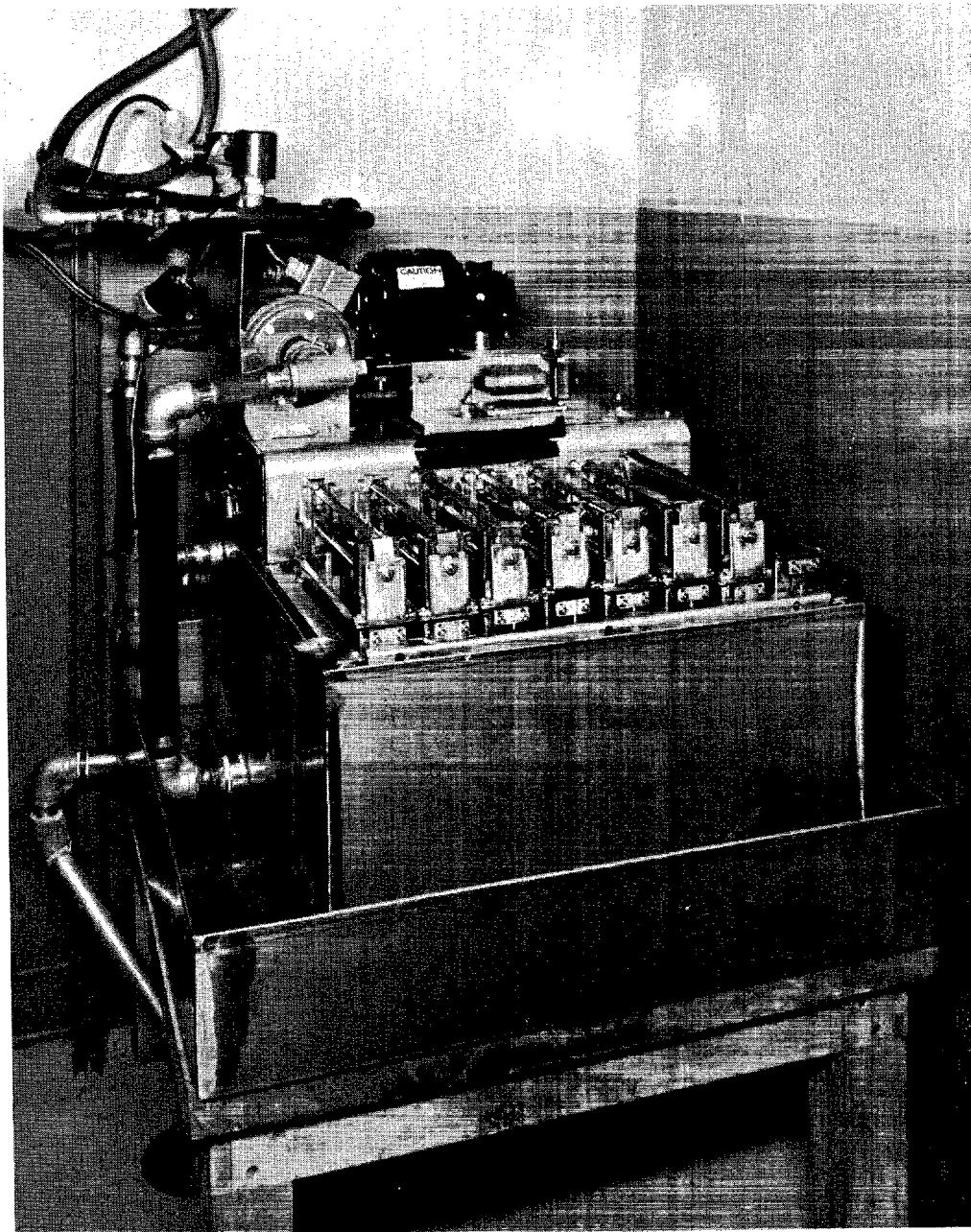


Figure 1. Small Capacity Sensitometric Processing Machine

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Table 2

DEVELOPMENT CONDITIONS FOR SENSITOMETRIC PROCESS

<u>Film</u>	<u>Developer*</u>	<u>Time</u> (Min.)	<u>Temperature</u> (°F)	<u>Gamma</u>	<u>Aerial Speed</u> <u>Index</u> (at 0.6 Gamma)
4400	AH-3	8	68	0.81	9.6
	AH-4	11	68	0.87	14.8
	AH-15	2	68	0.93	5.9
	AH-18	10	68	0.77	27.5
4401	AH-3	12	68	0.88	47.9
	AH-4	14	68	0.85	47.9
	AH-15	2.5	68	0.78	25.0
	AH-18	14	68	0.78	79.5
4404	AH-3	4	68	0.73	0.77
	AH-4	5	68	0.78	1.02
	AH-15	1	68	0.78	0.81
	AH-18	4	68	0.76	1.94

* Developer formulas are given in Attachment 1.

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7. Measurements**a. Acutance**

(1) Of the image structure parameters studied in this project, the one of primary interest was that of image edge quality. The fundamental importance of edges comes from their dual role in determining the subjective impression of sharpness (i.e.: definition) and in their role as the boundaries for linear mensuration. Among image quality measurements, edge evaluation appears to be the least precise and probably the least accurate. Two edge evaluation techniques are currently in use: acutance, and modulation transfer function derived from edges. Only the former method was used in this film/processing study for it is the simpler method and has been in use a longer time. Both methods are controversial at the present time.

(2) Acutance was proposed by Higgins and co-workers (see Reference 1) as an objective measurement having correlation with the subjective sensation of sharpness in a photograph. It is a laboratory measurement that has substantially reduced the necessity for extensive psychometric testing of new photographic products. The procedure is to expose a film in intimate contact with an opaque, sharp knife edge. After processing, the resultant image is traced on a microdensitometer. The microdensitometric data are reduced by hand or computer methods to yield acutance values as a function of the incident exposure. The maximum value for this curve is given as the single acutance number for the film/processing combination under test.

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(3) In undertaking this project, it was necessary to provide a large number of acutance exposures. An exposing device* was built (see Figures 2, 3, and 4) consisting of a knife edge, light source, line voltage regulator, and timer mounted in a light-proof box. The knife edge is a sharp edge exposed on a high resolution photographic plate. In the light path ahead of the knife edge is a carbon step tablet used to modulate the exposure along the edge. The light source is a small tungsten filament lamp and the light path is folded by means of a front-surface mirror so that the exposing light is reasonably specular. The film under test is held by vacuum contact during exposure.

25X1 (4) A Model 5 microdensitometer was used to scan the samples. This instrument (see Figures 5 and 6) is provided with both strip chart recorder and direct card punching capability. This latter facility, and ready access to I.B.M. 1620 and 7044 digital computers, permitted the reduction of large volumes of acutance data. The FORTRAN program, written for the acutance computations, is given in Appendix 1.

(5) While acutance measurements have shown correlation with subjective definition, it has not been shown that acutance and capability for linear mensuration are correlated, although this would intuitively seem to be the case.

(6) Acutance values found for the different film/processing combinations are compared in Figures 7, 8, and 9.

* This equipment represents the only item fabricated under PAR 211. Other instruments and hardware mentioned in this report were procured or built under other programs.

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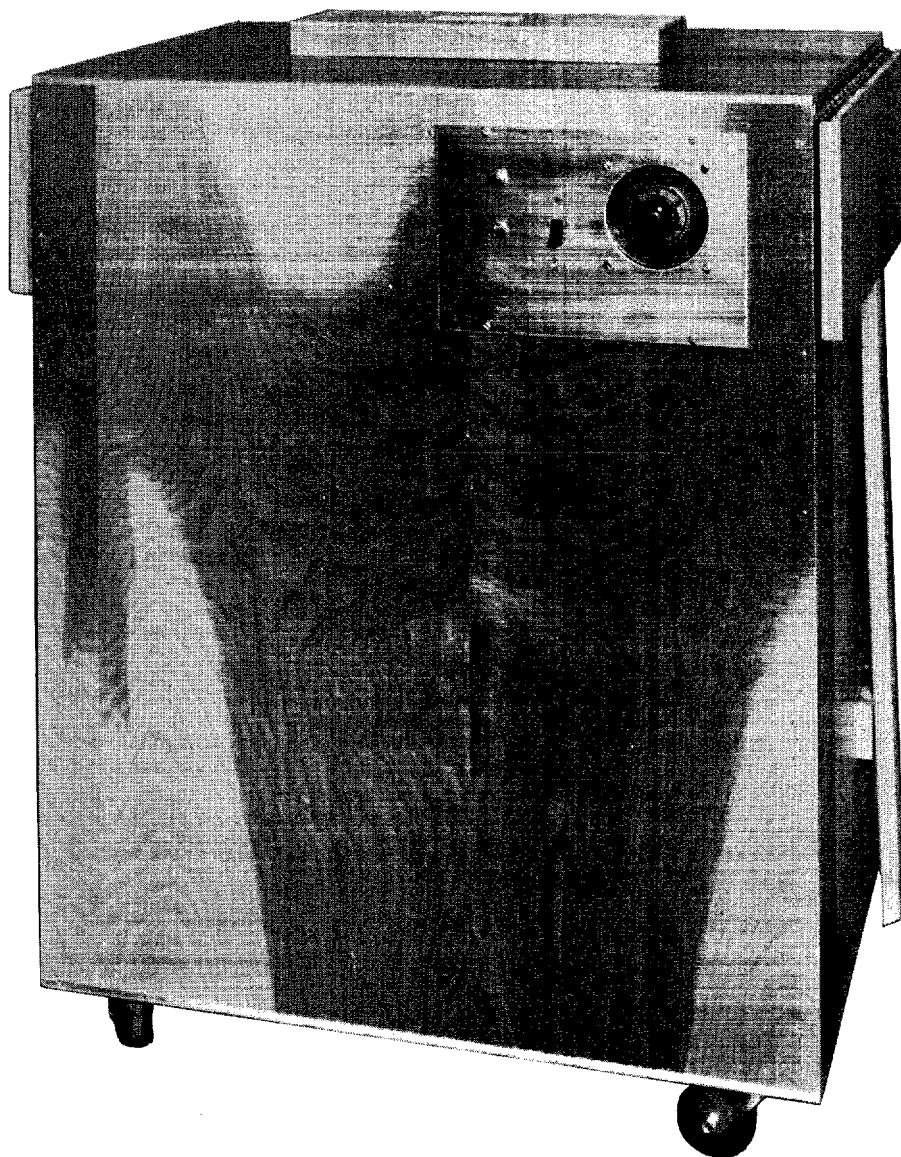


Figure 2. Acutance Exposure Printer:
Knife Edge Plane at Top (Covered)

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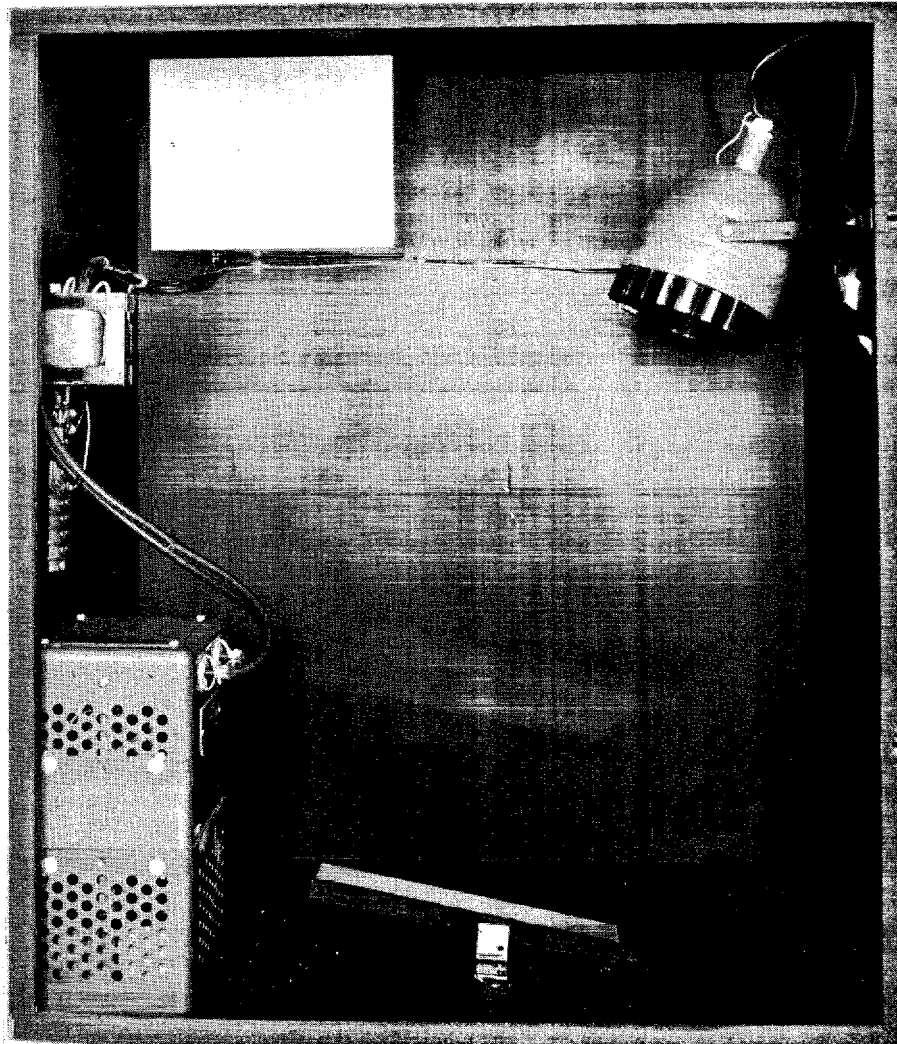


Figure 3. Interior of Acutance Printer:
Power Supply, Lamp and Inclined Mirror

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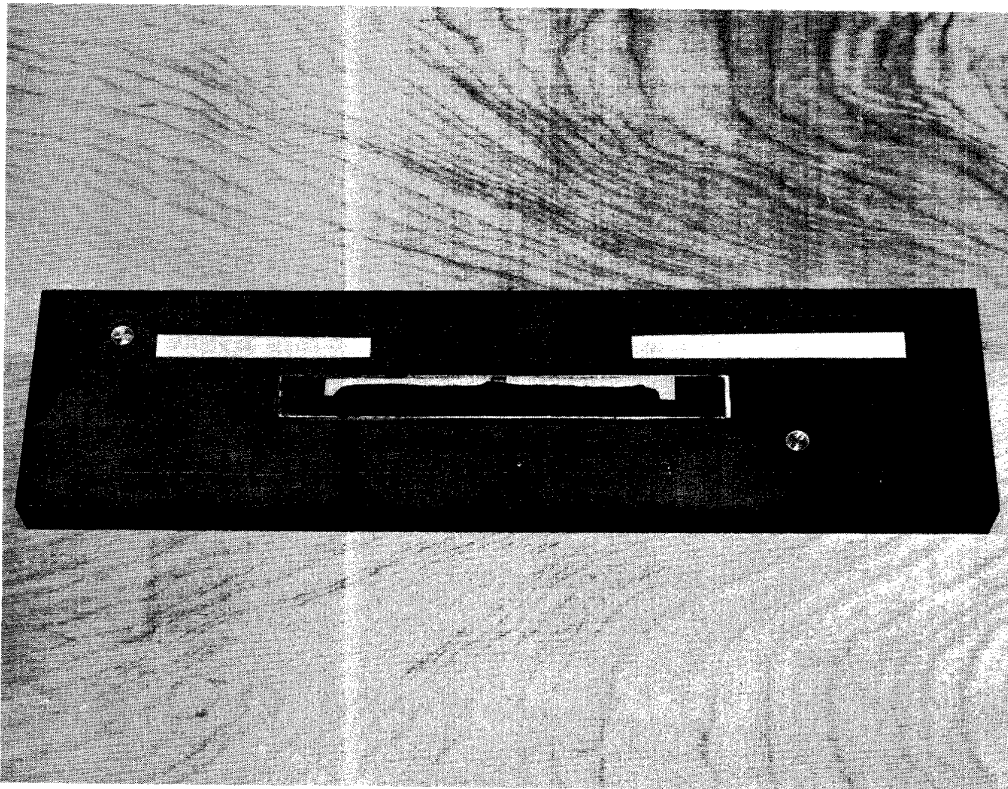


Figure 4. Top of Acutance Printer: Knife Edge with Step Tablet

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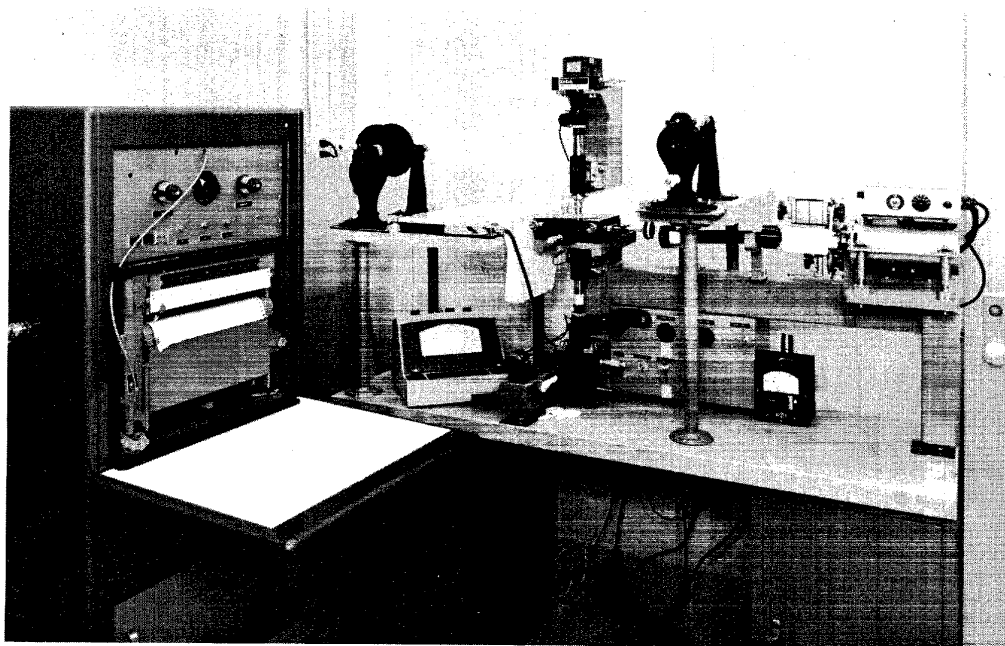


Figure 5. Model 5 Microdensitometer: Optical and Recording Apparatus

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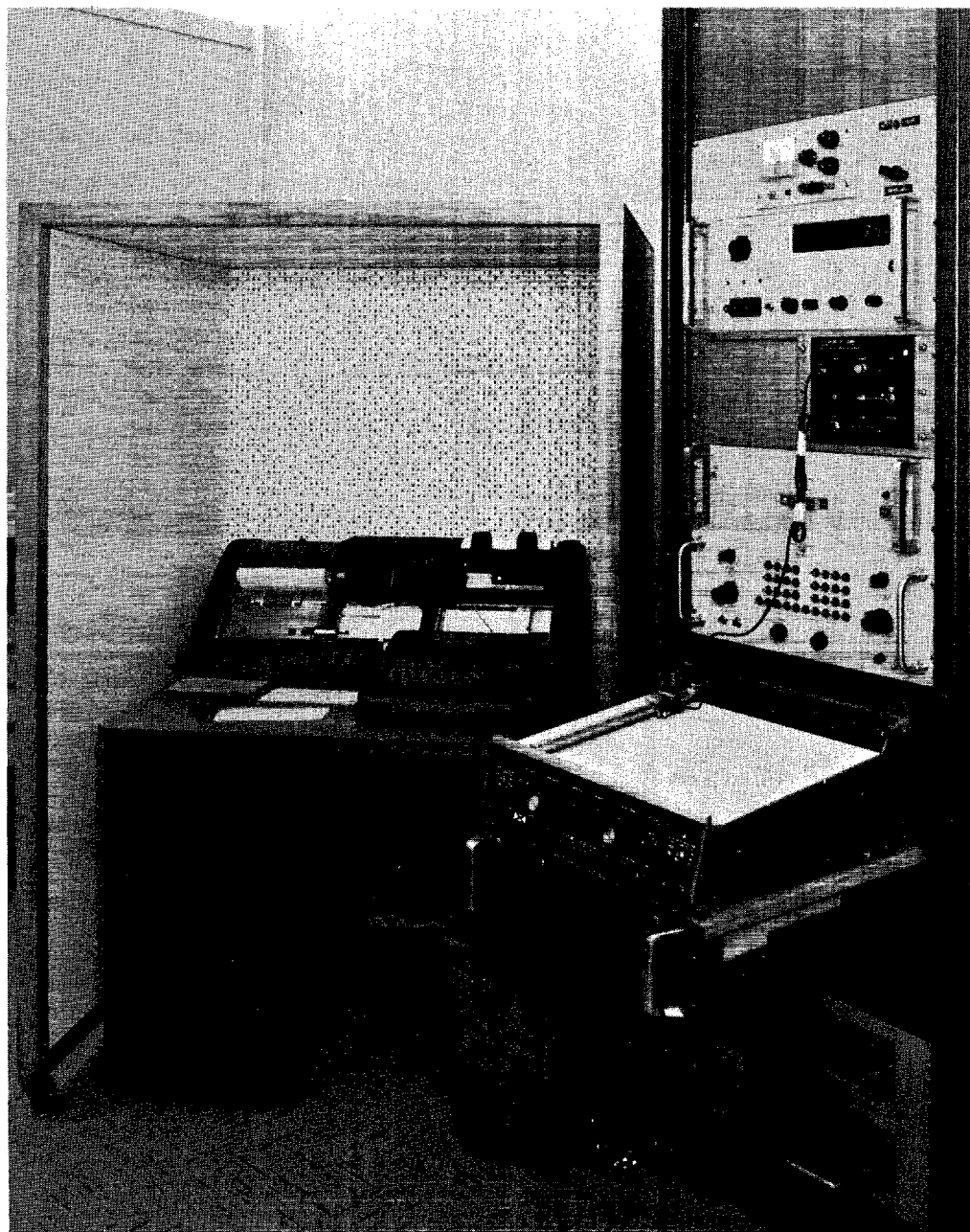


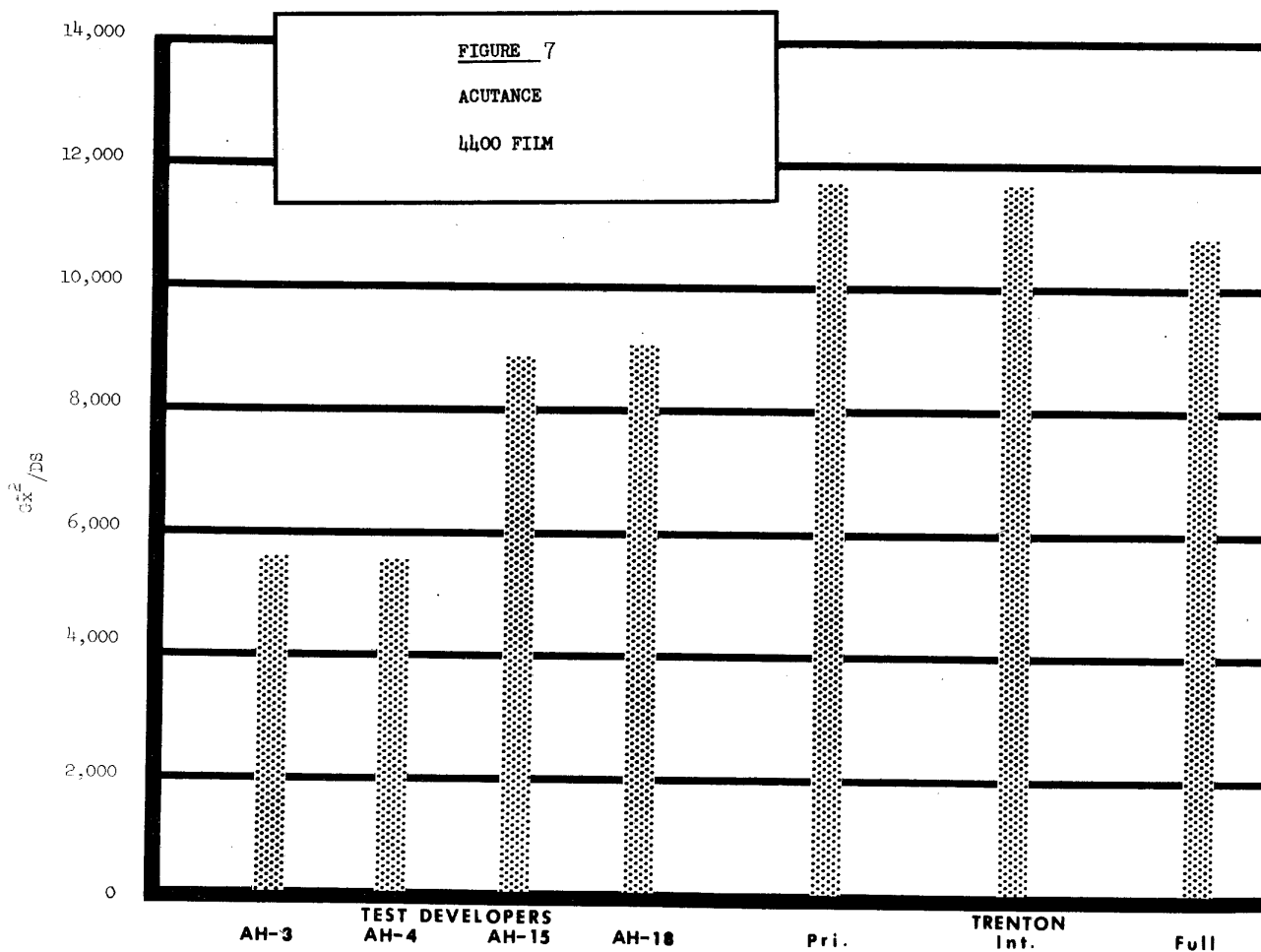
Figure 6. Model 5 Microdensitometer:
Data Converter and Card Punch

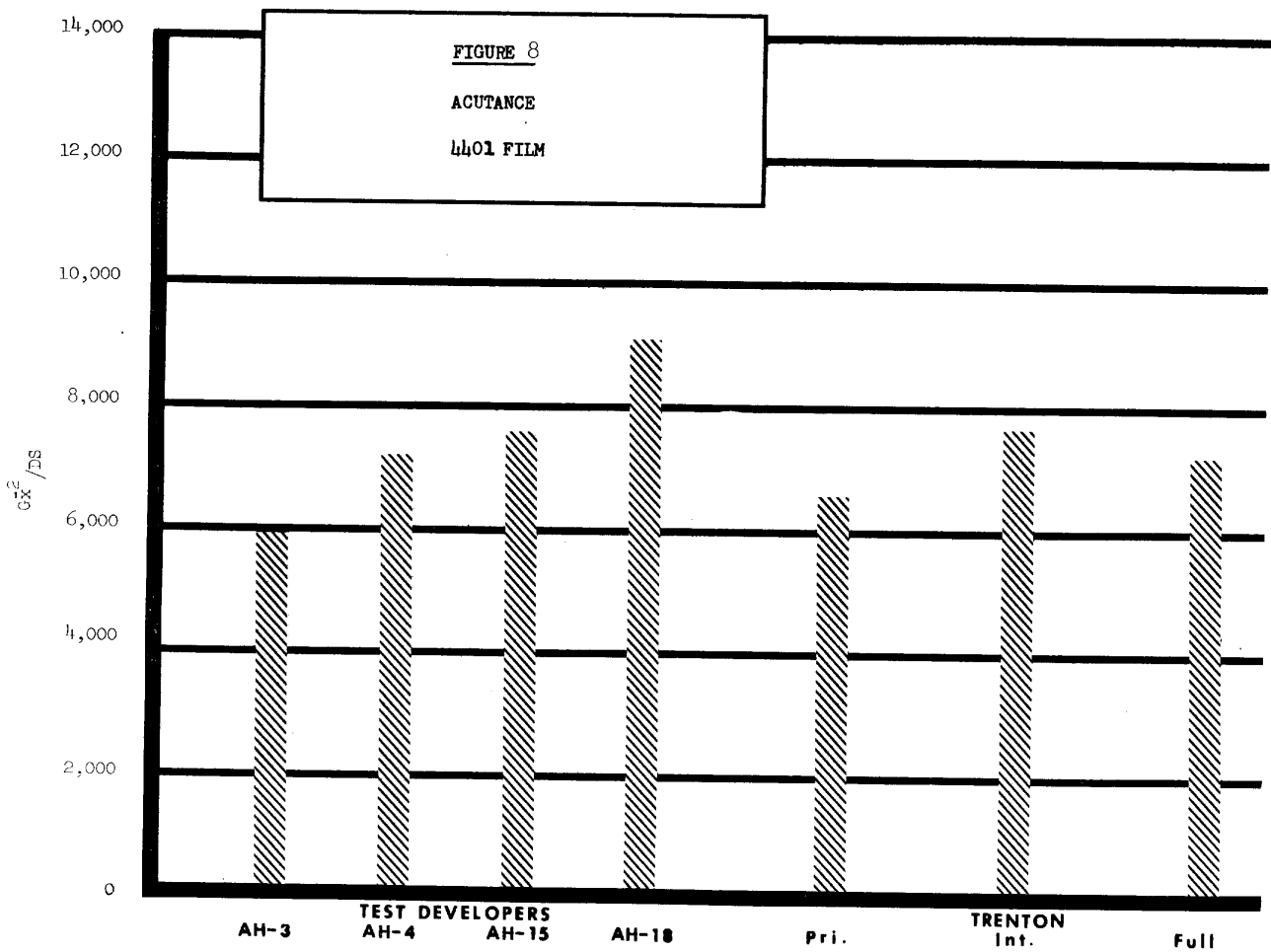
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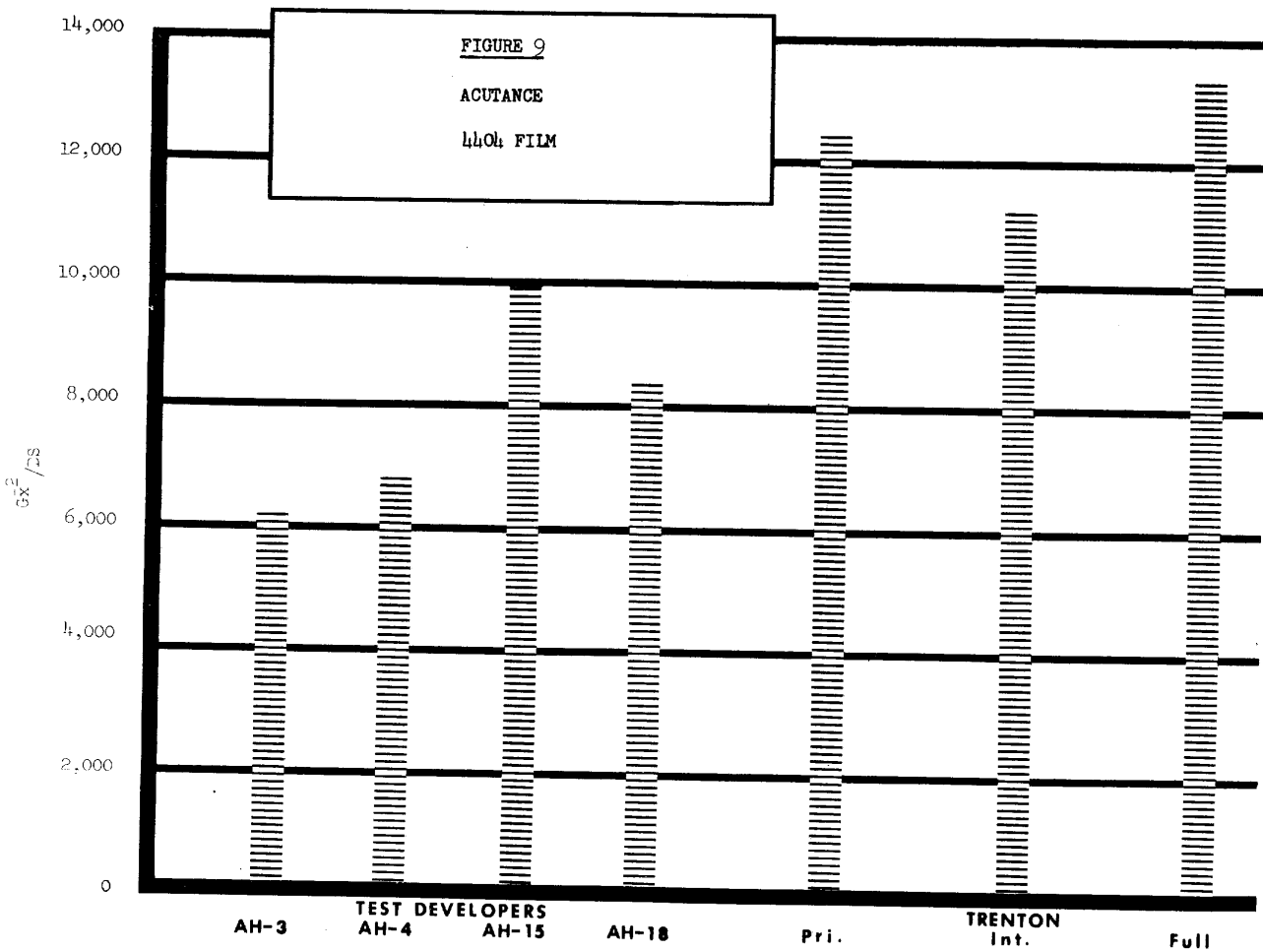
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b. Granularity

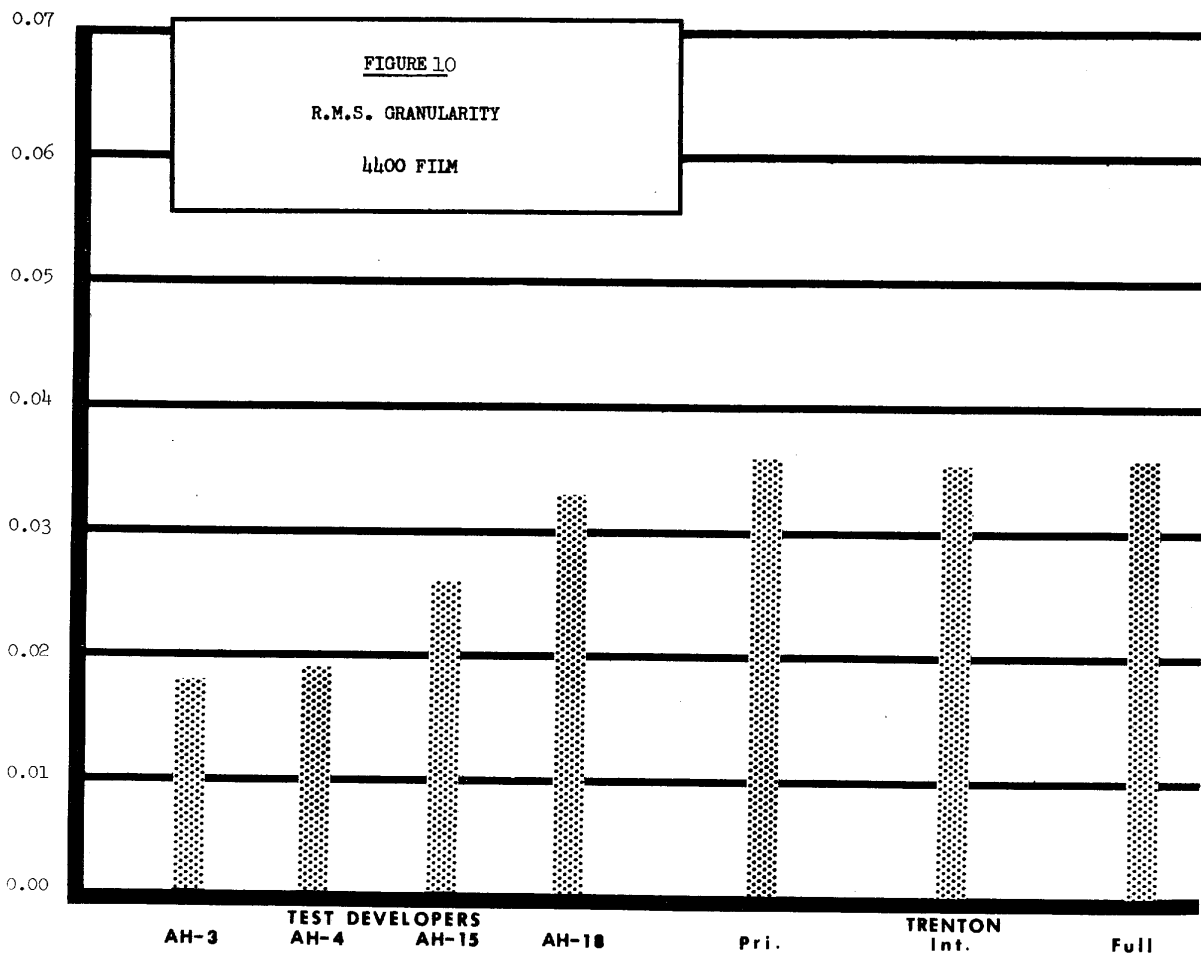
(1) Photographic images appear to be homogeneous when viewed without magnification. Upon magnification, the image separates into individual grains or clumps of grains. This lack of homogeneity is the noise component of photography as a communication channel (see Reference 2), and its measure is called granularity. The granularity or graininess of an emulsion sets one of the fundamental limits to the recognition of fine detail in any photographic system. Graininess also directly influences error in linear mensuration. For these reasons, the minimization of graininess through choice of processing techniques is of interest in photoreconnaissance systems, and was included as an image structure parameter studied in this project.

(2) Altman (see Reference 3) has described the method of making granularity measurements. Briefly, this method determines the standard deviation of density about some mean density through the use of a microdensitometer. In this project, the scanning aperture was 24 microns in diameter. A curve is plotted relating the granularity values obtained at a series of exposures versus density, and the granularity is interpolated from this curve at a density of 1.0 above base plus fog.

(3) Root Mean Square Granularity values obtained are compared in Figures 10, 11, and 12.

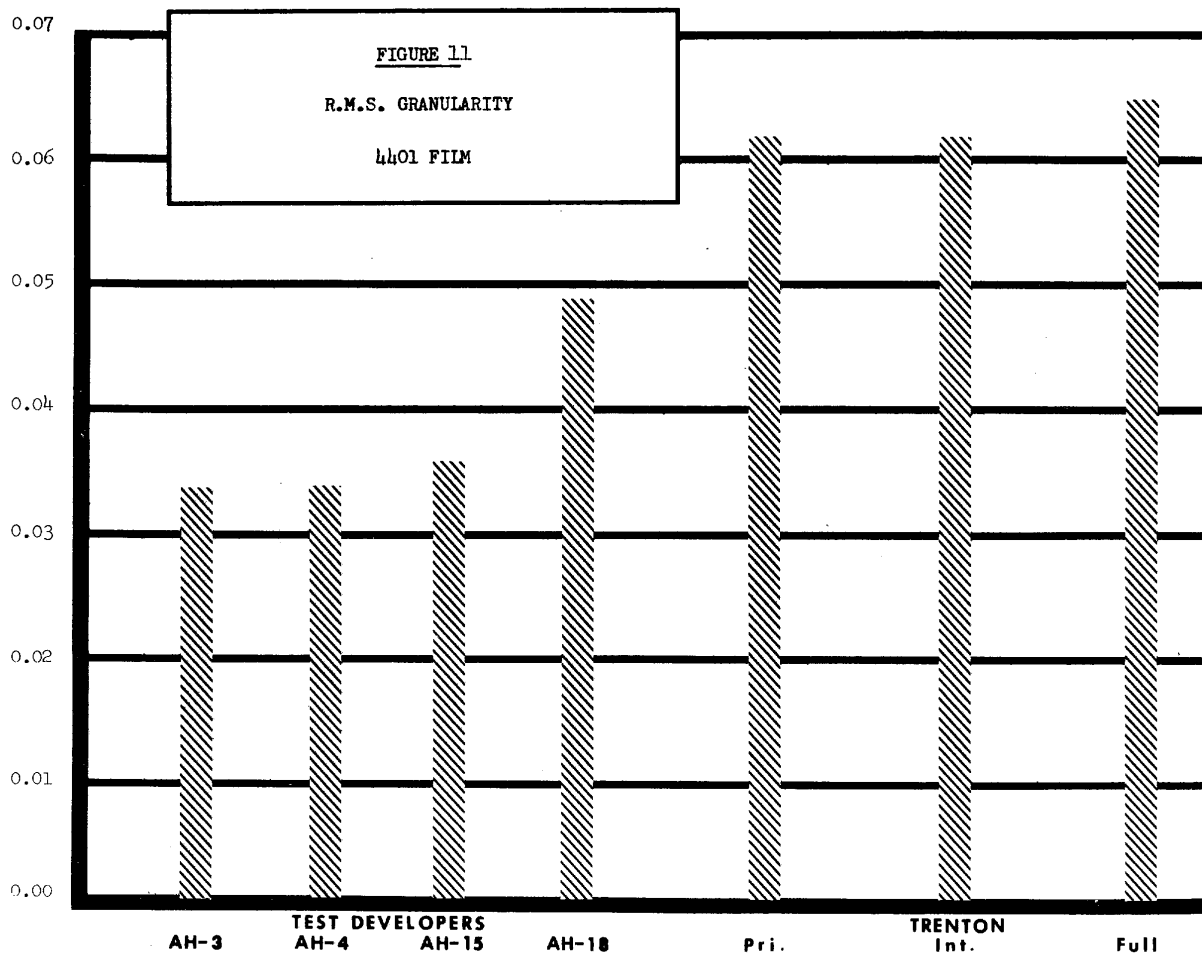
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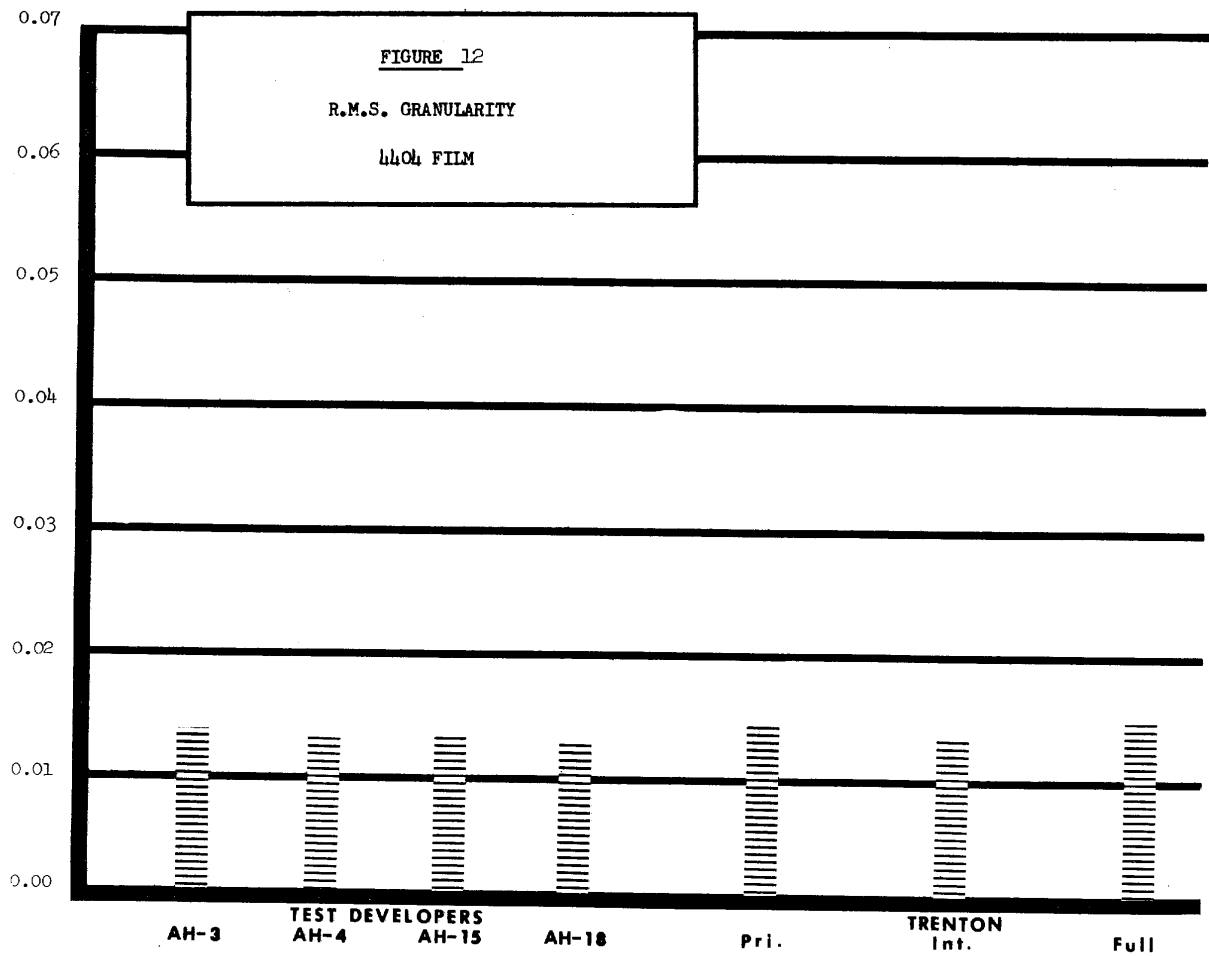
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c. Low Contrast Resolving Power

(1) The single image structure measurement most directly correlating with the ability to recognize small details in a photographic scene is resolving power. It is also the oldest method used to characterize the image quality of a photographic system. (Reference 2.) In one measurement are combined the components of signal and noise. Such a threshold determination is by nature low in precision, and this is particularly true for resolution data at low contrast.

(2) Where possible, measurements were made in accordance with the proposed American Standard Method for Determining Resolving Power of Photographic Materials (1963). Two departures from the tentative specifications were the following:

(a) A USAF 1951 sixth-root-of-two test object was substituted for the proposed twentieth-root-of-ten chart specified.

(b) Achromatic objective lens and matching ocular lens working in restricted wavelength light (540 mμ) were used in place of the proposed apochromatic objective to be used with white light.

These changes from the proposed specification were made so that the measurements would conform with the general practice at this facility during the evaluations. The contrast ratio of the exposures incident on the film under test was approximately 1.6 to 1 (log value 0.2 ± 0.02). Readout of processed film was made with a high quality binocular microscope having several levels of magnification and illumination. An exposure series was made on the film being evaluated, and the resolution value recorded for that strip was the maximum found on the strip.

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(3) The resolution target camera used in this project is shown in Figure 13.

(4) Resolution test data is compared in Figures 14, 15, and 16.

d. Modulation Transfer Function

(1) The determination of the modulation transfer function is an image structure measurement characterizing only the signal portion of the signal to noise ratio in a photographic system. While the mathematics of the method and its justification as a measuring tool are somewhat involved, it may suffice to say that any test object pattern may be synthesized from sinusoidal patterns; and that if a set of sinusoidal patterns varying in wavelength is photographed on a film, the degradation of the waves can be used to compute the degradation expected of any pattern. The film/processing portion of a photographic system is one low-pass filter element of that system (see Reference 4). Lens response, image motion, etc., are additional elements of the system which may be combined by cascading to give the system response.

(2) The modulation transfer measurements made in this project were exposed on equipment described by Lamberts (see Reference 5). White light (tungsten) was used in all cases. The exposures were scanned with a Kodak Model 3 microdensitometer.

(3) Partial testing covered only the developers used in sensitometric processing. The data for these tests are illustrated in Figures 17, 18 and 19.

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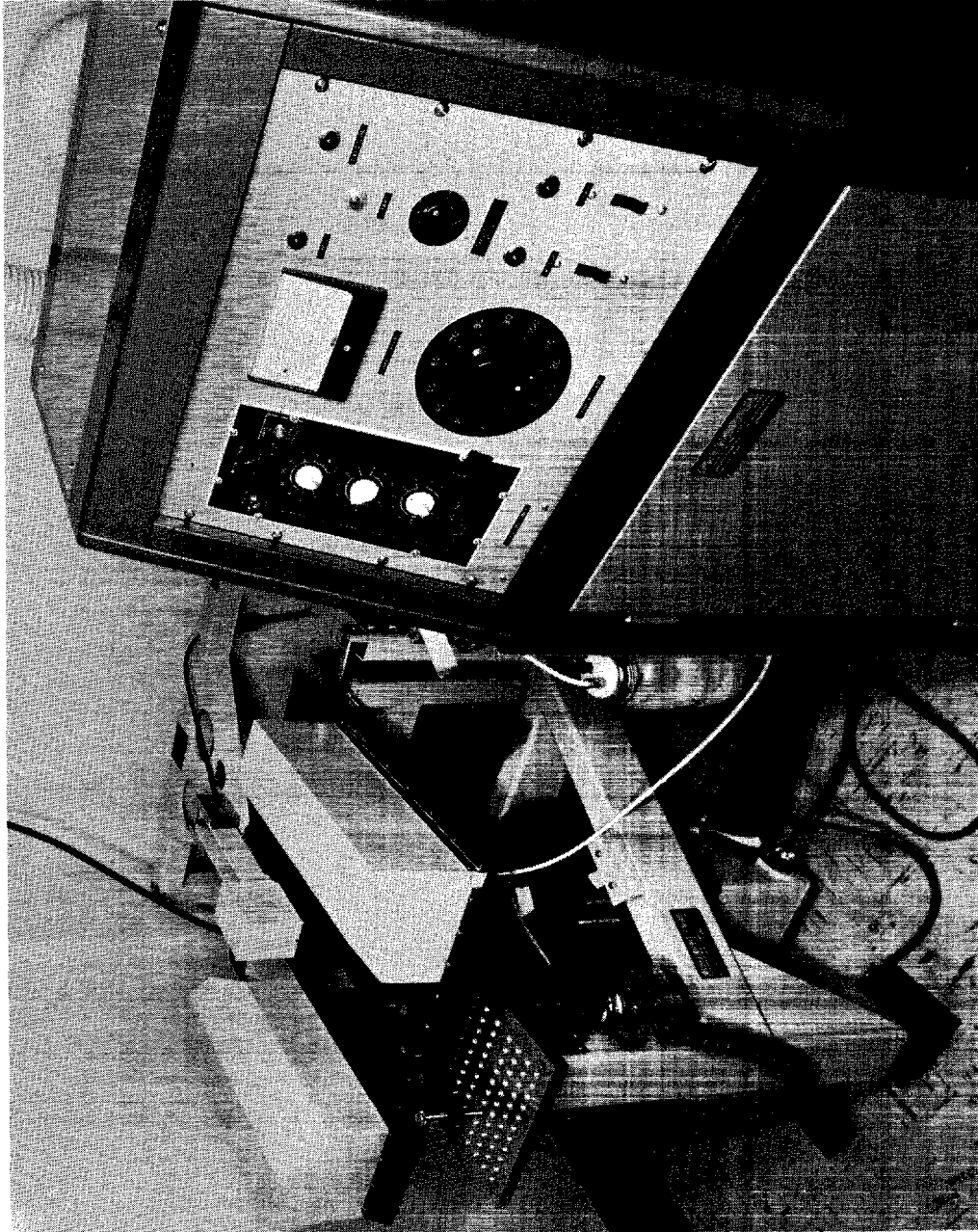
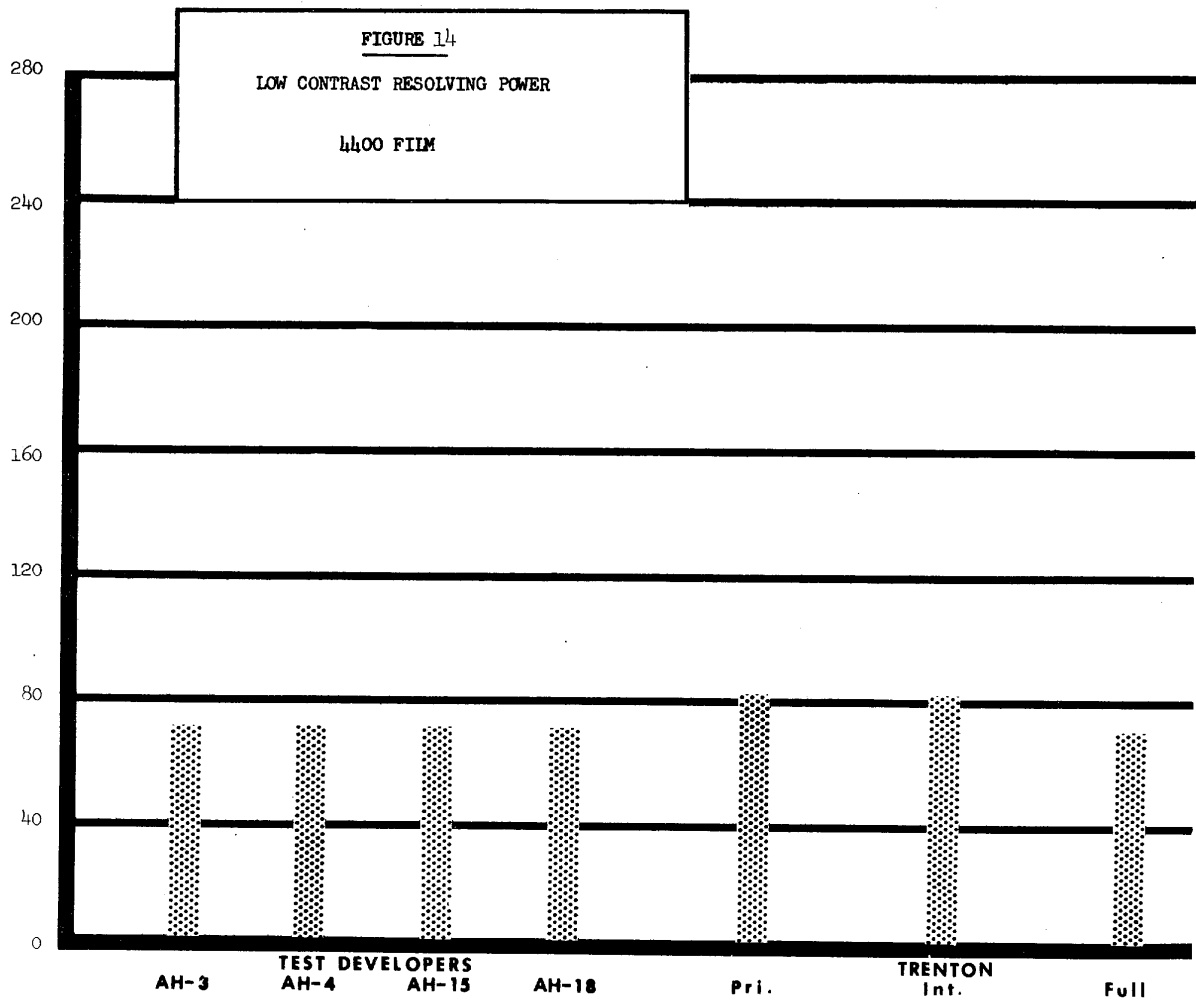


Figure 13. Resolution Target Camera and Control Console

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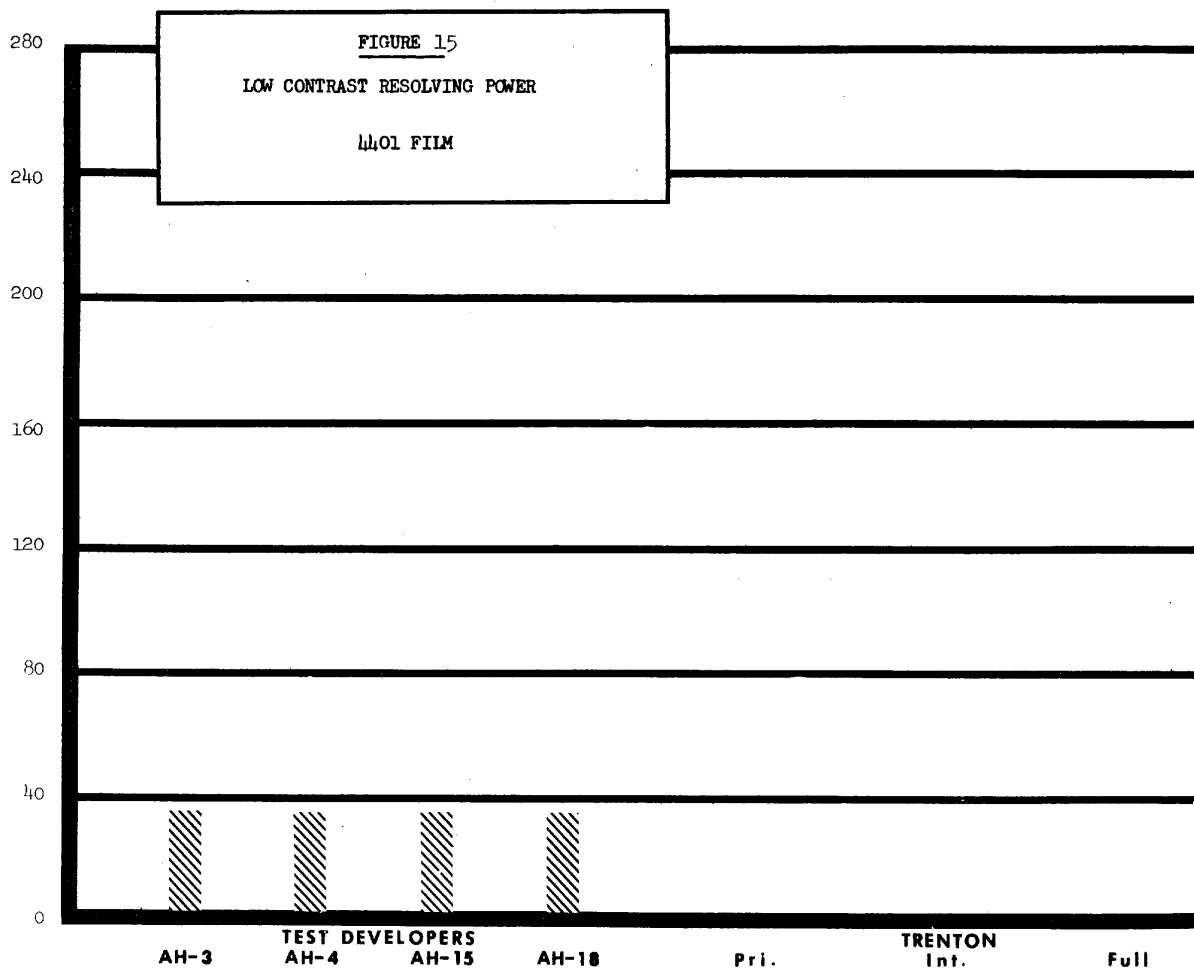


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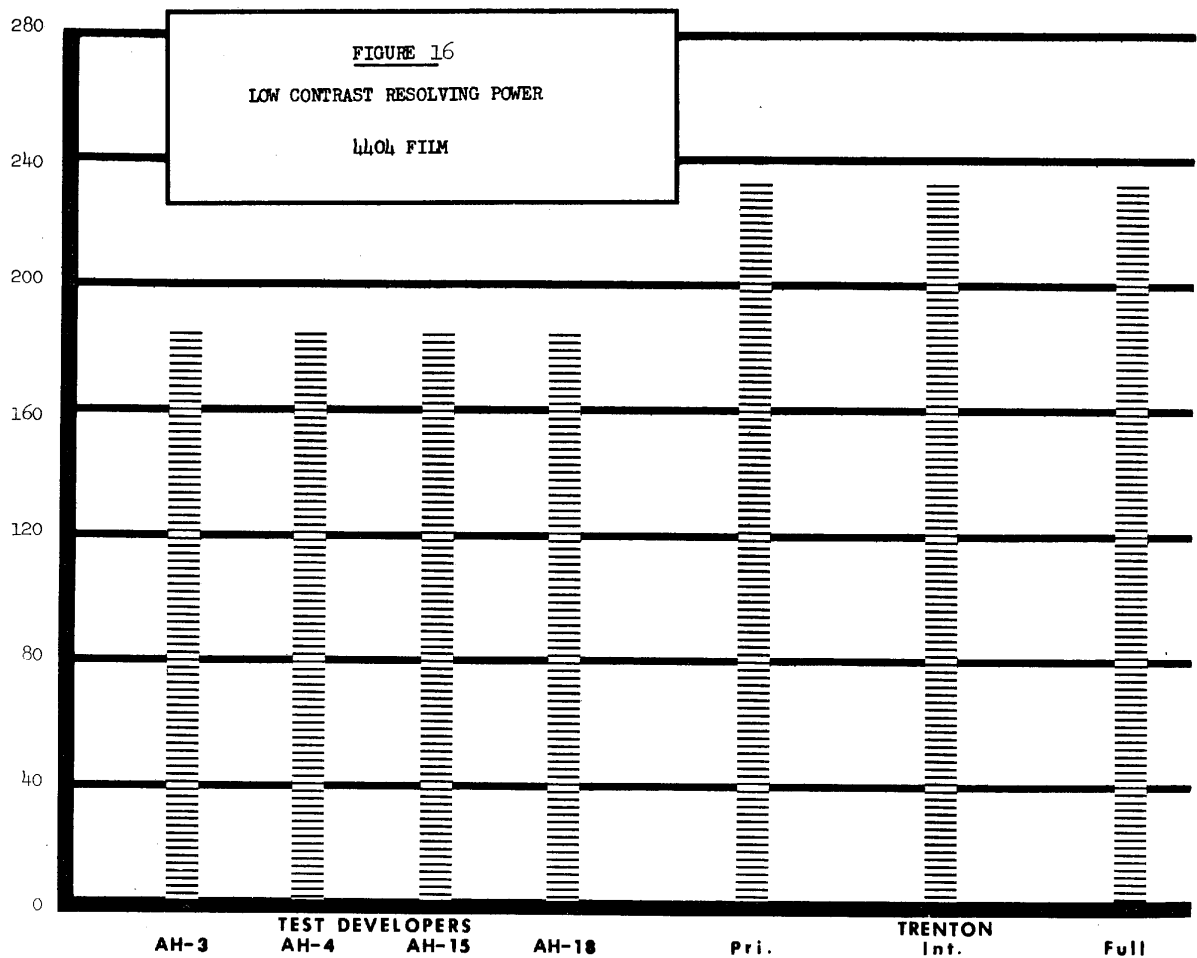
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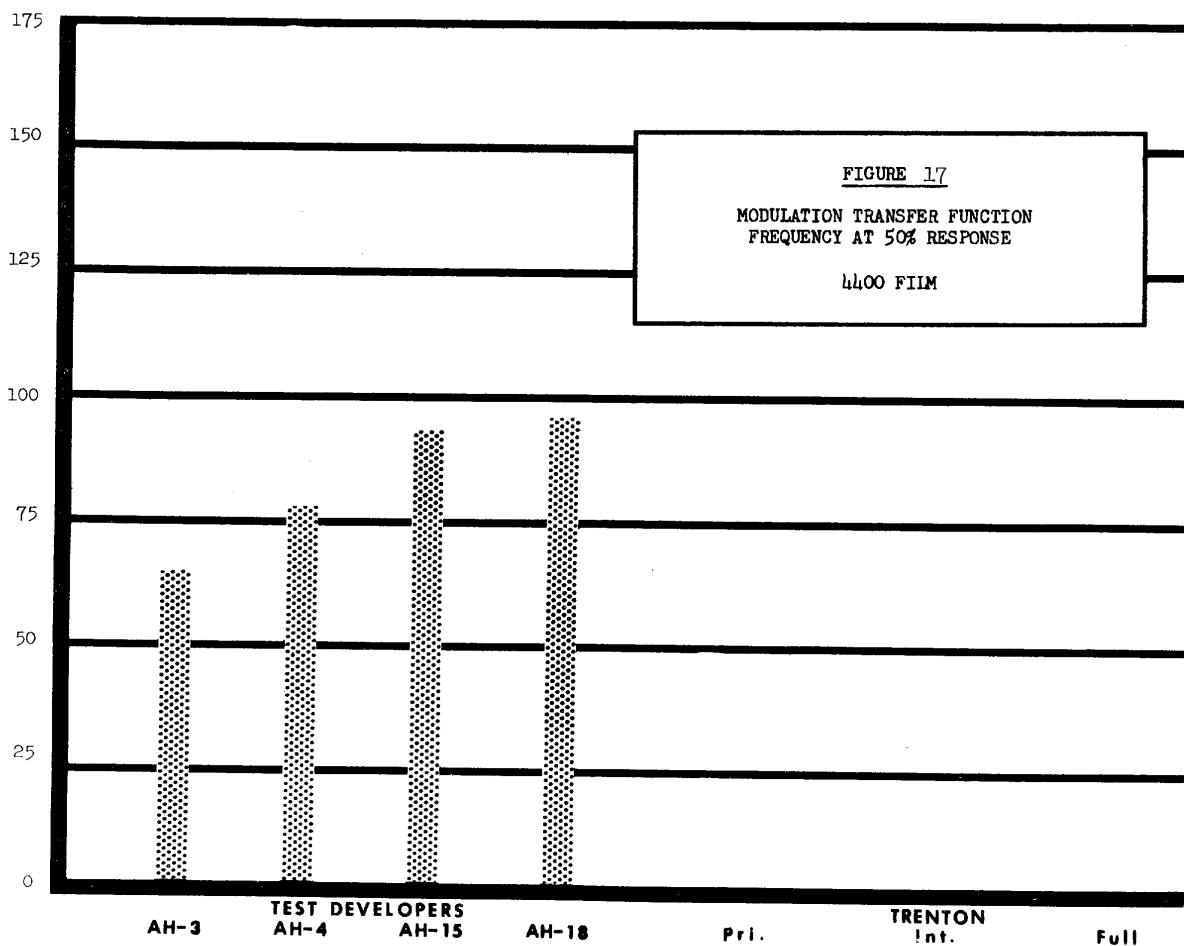
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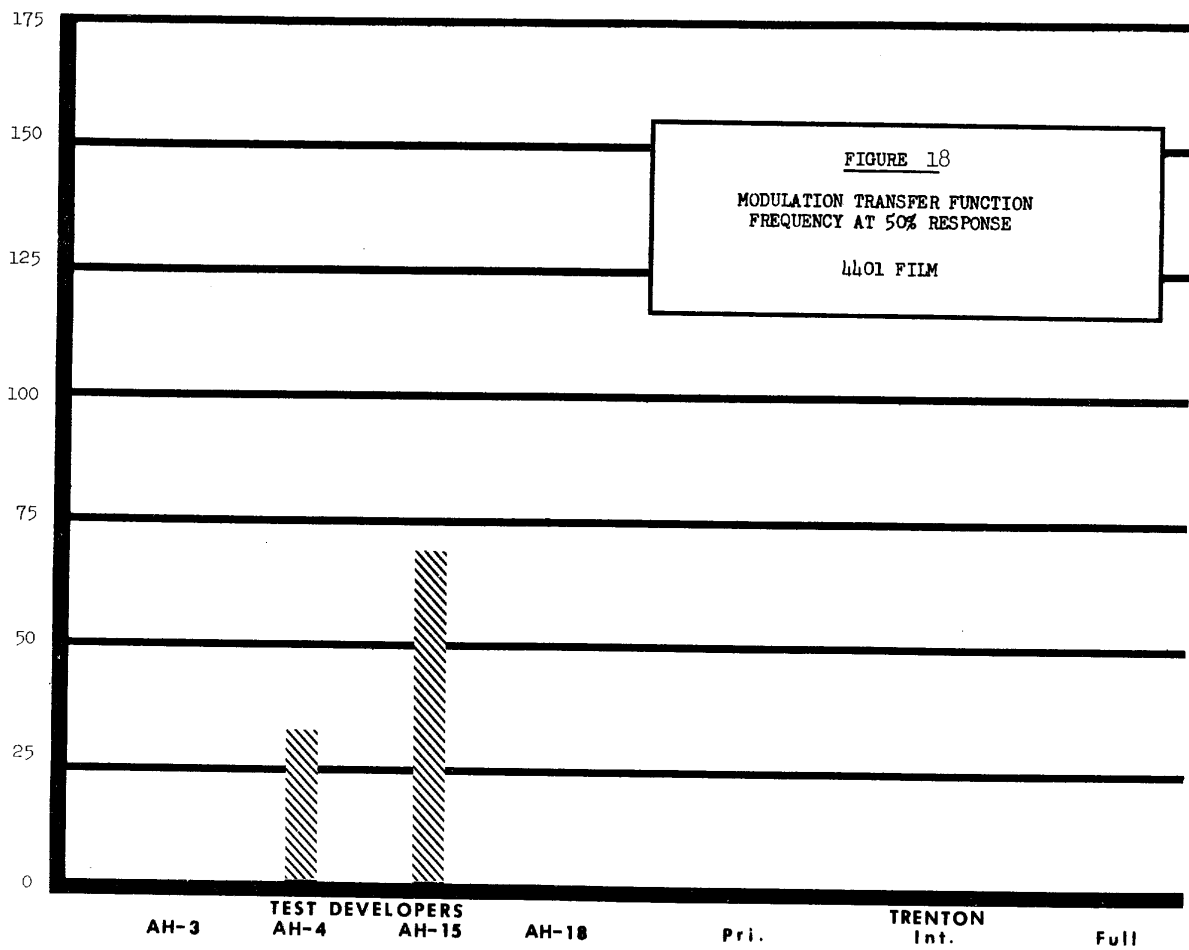
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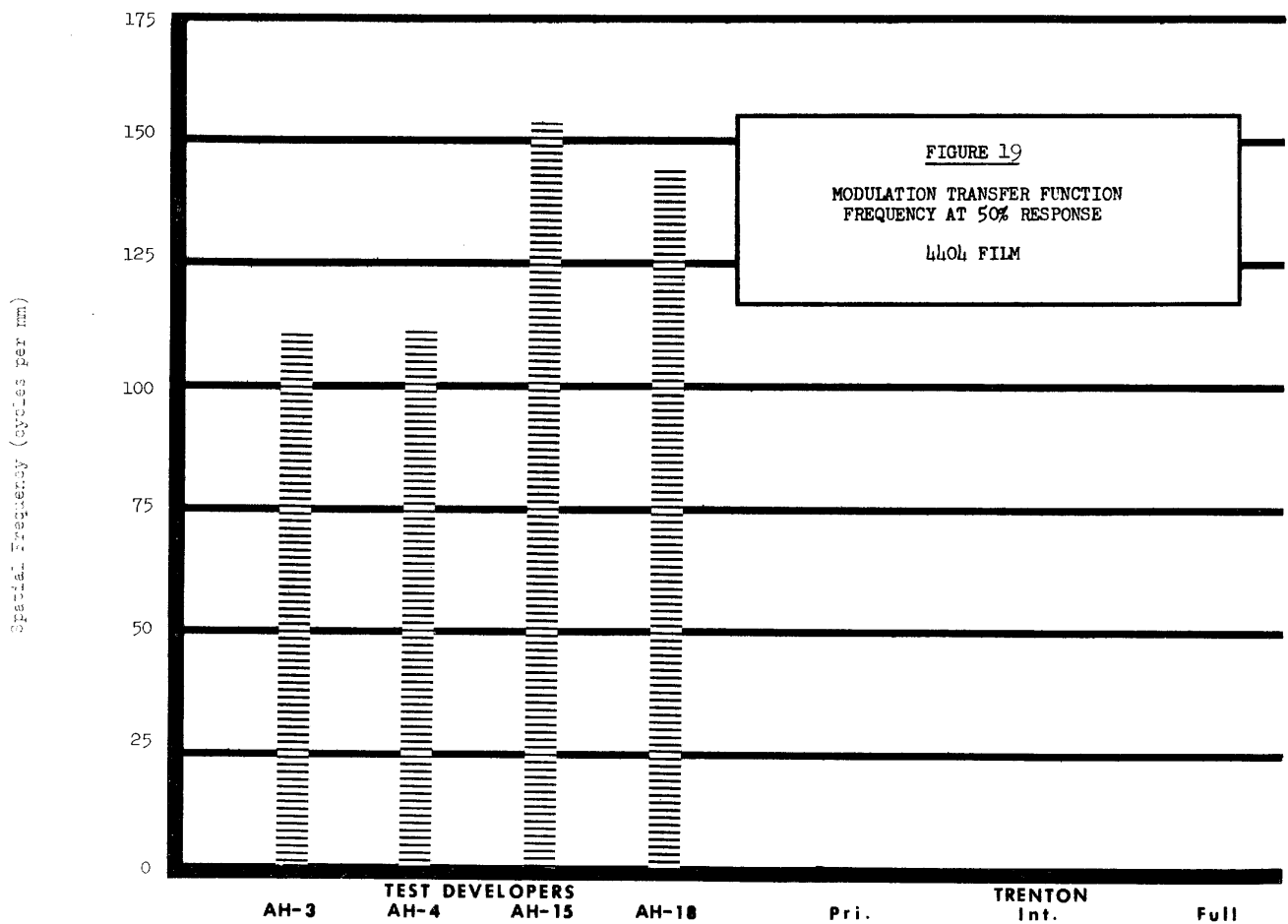
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8. Results

a. Image structure data consisting of acutance, granularity, low contrast resolving power, and modulation transfer function were collected on three aerial negative films, types 4400, 4401, and 4404 having seven processings. Standard Trenton three-condition processing was compared with four special formulations designed to give either low granularity or high sharpness. The acutance and granularity measurements for all film/processing combinations were completed, but only approximately two-thirds of the combinations of films and developers were measured for low contrast resolving power and modulation transfer function.

b. The measurements indicate that standard Trenton processing produces higher acutance, better low contrast resolving power, and poorer granularity as compared to the four special developer formulations. Because only partial results are known for modulation transfer function, no comparison of the two types of processing is possible.

c. Results are summarized by the data shown in Table 3. This table lists the values shown by histograms of Figures 7-12 and 14-19.

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TABLE 3

Image Structure Results for Various Chemical Developers

DEVELOPMENT	LOW CONTRAST RESOLVING POWER (LINES/MM)			ACUTANCE σ_X^2/DS			R.M.S. GRANULARITY $\sigma(D)$			MODULATION TRANSFER FUNCTION, FREQUENCY AT 50% RESPONSE		
	FILM			FILM			FILM			FILM		
	4400	4401	4404	4400	4401	4404	4400	4401	4404	4400	4401	4404
AH-3	73	38	185	5650	5950	6200	.018	.034	.014	65	--	111
AH-4	73	38	185	5600	7200	6800	.019	.034	.014	77	33	111
AH-15	73	38	185	8900	7600	9900	.026	.036	.014	93	69	155
AH-18	73	38	185	9100	9100	8400	.033	.049	.013	96	--	146
TRENTON PRIMARY	82	--	233	11758	6612	12464	.036	.062	.015	--	--	--
TRENTON INTERMEDIATE	82	--	233	11732	7713	11272	.036	.062	.014	--	--	--
TRENTON FULL	73	--	233	10856	7272	13388	.036	.065	.015	--	--	--

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CONCLUSIONS

9. The image structure of 4400, 4401, and 4404 film is affected by the type of developer used in processing. With composition changes, it is possible to optimize either sharpness, as measured by the parameter acutance, or graininess, measured as granularity, but it is not possible currently to combine the best sharpness and minimum graininess in a single developer formulation. Because such compromise is necessary, the choice of a developer may not be dominated by image structure criteria, but may be influenced by other characteristics such as the ability to control developed emulsion speed or tone reproduction requirements. The "informational sensitivity" of Zweig, et al (see Reference 6) or some such technique of convolving emulsion speed and image structure parameters might give a more quantitative measure of the effects of processing variations on typical aerial films.

10. Aerial simulations made at appropriate scales would have helped rank the significance of measured changes in acutance, granularity, resolution, or modulation transfer function. In absence of correlation with the subjective impression, it is difficult to assign weights to the image structure measurements for use in selection of developer formulas.

11. No significant advantage to further study is offered by introducing additional film types. Types 4400, 4401, and 4404 appear adequate as representative materials.

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RECOMMENDATIONS

12. At the termination of this project, several portions were left undone. For example, the modulation transfer function and low contrast resolving power measurements were not completed, and the aerial simulations for subjective evaluation had not been started. Medium contrast resolving power was proposed but not acted upon as a supplemental phase of the project. It is recommended that these portions of the project be completed so that the influence of processing on image structure characteristics can be evaluated both objectively and subjectively.

13. A study phase of this project considered the problem of linear mensuration at or near the limit of resolution. The key to both accuracy and precision of mensuration lies in establishing the "true" location of the edge. This is the position the edge would have had in the image if any point in the object registered as an unbroadened point in the image. Two programs are recommended, aimed at aiding the determination of the "true" edge location in mission photography. Both methods require the use of the high quality measuring instruments and large scale computer available to the customer. The first method involves determination of the spread function of an edge, and the second attempts an increase in the signal-to-noise ratio in the area of the image in which the mensuration object is located.

a. Any edge in the scene becomes broadened in the photographic image. Light diffusion within the emulsion, diffraction, aberrations, and defocusing of the lens, and uncompensated image motion are some of the factors

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contributing to this broadening. While it is not generally possible to know the amount of each factor individually at any place in an image, the combined spreading can be estimated from either line images or from long, straight edges by microphotometer scanning and computer data transformation. It is known that line and edge tracing generally lack precision, but it may be that one or more edges traced within the frame near or perhaps including the mensuration object would yield information on the direction and amount of edge broadening. This information could then be used to establish the "true" edge location.

b. Another possible approach in dimensioning near the limit of resolution is that of the techniques involving autocorrelation, cross correlation, and optimum filtering used in communication theory (see Reference 7). Hawkins (Reference 8), Kozma and Kelly (Reference 9), and Thiry (Reference 10), have proposed techniques for increasing the signal-to-noise ratio of photographic edges through optical spatial filtering. It would seem possible to accomplish the same spatial filtering in a digital computer working from information supplied by scanning the original negative with a microphotometer. The problem is that of detection of an aperiodic signal of known shape (an edge), of unknown pulse width (object length) in the presence of noise (photographic granularity). While the purpose may be different, there seems precedence in this approach in the studies conducted on the detection of radar and sonar signals in their normally noisy environment.

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APPENDIX 1

FORTTRAN PROGRAM FOR ACUTANCE CALCULATION

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```

C DATA ANALYSIS PROGRAM, S.PERRY MAY 25, 1965 NO.29-L (7044)
C ALTERED DECK FOR BOTH DIAGNOSTIC OR PRODUCTION OUTPUT.
C TO GET DIAGNOSTIC OUTPUT PUNCH A 1 IN COL.45 ON DATA PARAMETER
C CARD FOR DATA ECHO AND A 1 IN COL.50 FOR OUTPUT OF ALL OTHER
C VALUES. A 1 PUNCH IN COL.55 WILL GIVE PUNCHED OUTPUT OF SMVOLT.
EQUIVALENCE (DSTMAG , TRVLRT)
DIMENSION SMVOLT(401),RWVOLT(401),DATA(20),CALDEN(401)
DIMENSION TITLE(4), TITL2(4), XVOLT(25), YDENS(25)
C DEFINE MINIMUM CORCO, SAMPLING RATE, VELOCITY, LINEAR MAGNIFI-
C CATION
204 WRITE (6,136)
136 FORMAT(1H , 50H*** PRO-DIAGNO PROGRAM B.B. 29-L (MAY 25,1965)** )
119 READ(5,13)CORMIN,DIFMAX,MXSCH
13 FORMAT(2F10.2,110)
IF (MXSCH) 501,501,500
501 MXSCH = 7
500 IF(MXSCH.GT.100)GO TO 999
WRITE(6,120)CORMIN,DIFMAX,MXSCH
120 FORMAT(1H0,21HMIN. CORCO ALLOWED = ,F7.2,5X,
225HMAX. 4TH DIFF. ALLOWED = ,F7.2 /21HSLOPE SEARCH RANGE = ,I6)
205 READ(5,10)TRVLRT,SMPLRT
10 FORMAT(2F10.3)
IF (TRVLRT) 87, 87, 101
87 WRITE(6,102)
102 FORMAT(1H ,16HNO TRVLRT NUMBER)
GO TO 999
101 IF (100. - TRVLRT) 8, 8, 7
8 MTEST = 1
WRITE(6,121)DSTMAG
121 FORMAT(1H ,14HLINEAR MAG. = ,F12.2)
C COMPUTE INCREMENT OF X
DELTX=2540./DSTMAG
GO TO 88
7 MTEST = 2
WRITE(6,122)TRVLRT,SMPLRT
122 FORMAT(1H ,17HRATE OF TRAVEL = ,F8.4,5X,
221HSAMPLES PER MINUTE = ,F8.1)
DELTX=1000.*TRVLRT/SMPLRT
88 WRITE(6,114)DELTX
114 FORMAT(1H ,8HDELTX = ,F10.3)
C READ CODE NO. AND XFOG
11 READ(5,14)TITLE,XFOG
14 FORMAT(4A5,F10.2)
SDEN=0.
SDEN2=0.
SVOLT=0.
SVOLT2=0.
CNT1=0.
SXY=0.
C --- START CALIBRATION PROCEDURE
DO 15 N=1,25
READ(5,12)XVOLT(N), YDENS(N)
12 FORMAT(2F4.2)
IF(9.99-XVOLT(N))999,16,17
17 SDEN=SDEN+YDENS(N)
SDEN2=SDEN2+YDENS(N)*YDENS(N)

```

DATAN011
 DATAN010
 DATAN045
 DATAN050
 DATAX051
 DATAX070
 DATAN075
 DATAX076
 DATAX077
 DATAX100
 DATAN105
 DATAN106
 DATAX107
 DATAX108
 DATAN109
 DATAN110
 DATAN111
 DATAX091
 DATAX092
 DATAN095
 DATAN093
 DATAN094
 DATAN105
 DATAX106
 DATAX107
 DATAX108
 DATAN109
 DATAX110
 DATAX111
 DATAN110
 DATAX111
 DATAX112
 DATAN015
 DATAN020
 DATAN025
 DATAN030
 DATAN035
 DATAN040
 DATAX124
 DATAN125
 DATAN135

SECRET

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```
SVOLT=SVOLT+XVOLT(N)
SVOLT2=SVOLT2+XVOLT(N)*XVOLT(N)
SXY=SXY+XVOLT(N)*YDENS(N)
15 CNT1=CNT1+1.
C --- CALCULATE CORRELATION COEFFICIENT
16 CORCO=(CNT1*SXY-SDEN*SVOLT)/SQRT ((CNT1*SVOLT2-SVOLT*
2SVOLT)*(CNT1*SDEN2-SDEN*SDEN))
C CALCULATE THRESHOLD
GO TO (41, 42), MTEST
41 CRTSLP=12.7/DSTMAG
GO TO 43
42 CRTSLP=5.*TRVLRT/SMPLRT
C CALCULATE VOLT DATA CONVERSION COEFFICIENTS
43 SLOPE=(CNT1*SXY-SDEN*SVOLT)/(CNT1*SVOLT2-SVOLT*SVOLT)
YCEPT=(SDEN*SVOLT2-SVOLT*SXY)/(CNT1*SVOLT2-SVOLT*SVOLT)
IRUN=1
WRITE(6,100)CRTSLP
100 FORMAT(1H ,9HCRTSLP = ,F10.5)
WRITE(6,107)TITLE,XFOG
107 FORMAT(1H0,4A5,F10.2)
IF(CORCO-CORMIN)18,19,19
18 WRITE(6,20)CORCO
20 FORMAT(1H ,9HCORCO OF ,F7.3,4X,7HTOO LOW)
WRITE(6,300)
300 FORMAT(1H-,59HERRONEOUS DATA TO FOLLOW DUE TO LOW CORRELATION COEF
2FICIENT)
DO 308 I=1,N
308 WRITE(6,309) XVOLT(I), YDENS(I)
309 FORMAT(1H ,2F8.2)
GO TO 203
19 WRITE(6,22)CORCO
22 FORMAT(1H ,9HCORCO OF ,F7.3,4X,4HOKAY)
C READ DESIRED DEGREE OF SMOOTHING IN 1ST COL. AND NUMBER OF
C ITERATIONS IN 11TH COLUMN.
203 READ(5,44)IDGSMH,NITRTN,TITL2,KDATA,KVAL,KPUNCH
44 FORMAT (11, 9X, 11, 9X, 4A5, 4X, 11, 4X, 11, 4X, 11)
IF(IDGSMH)999,200,201
200 WRITE(6,202)
202 FORMAT(1H ,17HNO PARAMETER CARD)
GO TO 203
201 WRITE (6, 109) TITL2
109 FORMAT (1H0, 4A5)
GO TO (119,11,205,204,206,999,206,999,206), IDGSMH
206 DO 24 N=1, 400
SMVOLT(N)=0.
CALDEN(N) = 0.
24 RWVOLT(N)=0.
NOSMTH=1
N=1
28 READ(5,25)(DATA(I),I=1,20)
25 FORMAT(20F4.2)
IF(KDATA)999,303,304
304 WRITE (6, 123) (DATA (I), I = 1, 20)
123 FORMAT (1H , 20F6.2)
303 DO 26 K=1,20
J=K+N-1
```

DATAN170
DATAX174
DATAN175
DATAN180
DATAN185
DATAN190
DATAN195
DATAN200
DATAN205
DATAN210
DATAN215
DATAN220
DATAN225
DATAX226
DATAX227
DATAX228
DATAX229
DATAN235
DATAX240
DATAX245

DATAX255
DATAX260
DATAN265
DATAN266

DATAN276
DATAN277
DATAN980
DATAN280
DATAN285
DATAN286
DATAN290
DATAN295
DATAN300
DATAX305
DATAN310

DATAX311
DATAX312
DATAN315
DATAN320

SECRET

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```
26 CALDEN(J)=DATA(K)
N=N+20
IF(DATA(20))27,27,28
C BLANK VALUE IN 20TH COLUMN STOPS CARD READING
27 DO 29 MAX=1,N
IF (CALDEN(MAX))93, 93, 29
29 CONTINUE
93 MAX = MAX - 1
MXNUM = MAX
IF (CALDEN(MAX) - CALDEN (1)) 95, 81, 94
81 WRITE(6,104)
104 FORMAT(1H0,43HNO DIFFERENCE IN DATA FROM ONE END TO OTHER)
GO TO 99
94 DO 96 I = 1, MAX
96 RWVOLT(I) = CALDEN(I)
GO TO 30
C --- INVERT DATA
95 DO 97 I = 1, MAX
J = MAX - I + 1
97 RWVOLT(I) = CALDEN(J)
30 TEST = 0.5 * (RWVOLT(MAX) - RWVOLT(1)) + RWVOLT (1)
DO 55 I = 1, MAX
IF (RWVOLT(I) - TEST) 55, 86, 86
55 CONTINUE
WRITE(6,103)
103 FORMAT(1H ,21HCANNOT FIND MID POINT)
GO TO 99
86 IMAX = I
137 DO 105 I = 1, MXNUM
105 SMVOLT(I) = RWVOLT(I)
MAX = MXNUM
C START TO FORM 4TH DIFFERENCE TABLE
K=1
N = MAX
31 N=N-1
DO 32 I=1,N
32 SMVOLT(I)=SMVOLT(I+1)-SMVOLT(I)
SMVOLT(N+1) = 0.0
IF(KVAL)999,127,305
305 J = 1
126 L = J + 19
WRITE (6, 124) (SMVOLT (I), I = J, L)
124 FORMAT (1H , 20F6.3)
IF(N - J) 127, 127, 125
125 J = J + 20
GO TO 126
127 IF(K-3)33,33,34
33 K=K+1
GO TO 31
34 TEST=-99.
DO 35 I=1,N
IF(ABS (SMVOLT(I))-TEST)35,35,36
36 TEST=ABS (SMVOLT(I))
MAXERR=I+2
35 CONTINUE
JTEST=1
```

DATAN325
DATAN330
DATAN335
DATAN340
DATAN345
DATAN350
DATAN351
DATAN352
DATAX352
DATAN353
DATAX354
DATAX355

DATAN354
DATAN355
DATAN356
DATAX357
DATAN357
DATAN358
DATAN359
DATAN361
DATAN362
DATAN363
DATAN364
DATAX365
DATAX366
DATAN367
DATAN368
DATAN376
DATAN377
DATAN359
DATAN360
DATAN365
DATAN371
DATAN375
DATAN380
DATAN385
DATAN386

DATAX386
DATAX387
DATAX388
DATAX389
DATAX390
DATAX391
DATAX392
DATAN390
DATAN395
DATAN400
DATAN405
DATAN410
DATAN415
DATAN420
DATAN425
DATAN430
DATAN435

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```
C      TEST TO SEE WHETHER 4TH DIFF EXCEEDS MAX VALUE
      TSTMX = TEST
      IF (TEST-DIFMAX)37,38,38
38     WRITE(6,39)TEST,MAXERR,RWVOLT(MAXERR),IRUN
39     FORMAT(1H , 20X, 15HMAX 4TH DIFF OF , F7.3, 2X, 2HAT, 14, 4X,
      2    11HDATA POINT, 5X, F5.2, 5X, 14)
      JTEST=2
37     DO 56 I=1,400
      SMVOLT(I) = 0.0
56     CALDEN(I)=0.
C      SELECT DEGREE OF SMOOTHING
      GO TO (119,11,205,204,45,999,46,999,47), IDGSMH
C      START 5 POINT CUBIC SMOOTHING
45     MAX=MAX-2
      DO 40 I=3,MAX
40     SMVOLT(I)=(-3.*RWVOLT(I-2)+12.*RWVOLT(I-1)+17.*RWVOLT(I)+12.*
      2RWVOLT(I+1)-3.*RWVOLT(I+2))/35.
      GO TO 48
C      START 7 POINT CUBIC SMOOTHING
46     MAX=MAX-3
      DO 49 I=4,MAX
49     SMVOLT(I)=(-2.*RWVOLT(I-3)+3.*RWVOLT(I-2)+6.*RWVOLT(I-1)+7.*
      2RWVOLT(I)+6.*RWVOLT(I+1)+3.*RWVOLT(I+2)-2.*RWVOLT(I+3))/21.
      GO TO 48
C      START 9 POINT CUBIC SMOOTHING
47     MAX=MAX-4
      DO 51 I=5,MAX
51     SMVOLT(I)=(-21.*RWVOLT(I-4)+14.*RWVOLT(I-3)+39.*RWVOLT(I-2)+54.*
      2RWVOLT(I-1)+59.*RWVOLT(I)+54.*RWVOLT(I+1)+39.*RWVOLT(I+2)+14.*
      3RWVOLT(I+3)-21.*RWVOLT(I+4))/231.
48     IF (KVAL+KPUNCH)999,129,306
306    J = 1
131    L = J + 19
      IF (KVAL)999,311,312
312    WRITE (6, 128) (SMVOLT(I), I = J, L)
128    FORMAT (1H , 20F6.3)
311    IF (KPUNCH)999,313,310
310    WRITE(7,25)(SMVOLT(I),I=J,L)
313    IF (MAX - J) 129, 130, 130
130    J = J + 20
      GO TO 131
129    GO TO (52,53),JTEST
53     IF (NOSMTH - NITRTN) 54, 52, 52
54     NOSMTH=NOSMTH+1
      WRITE(6,60)RWVOLT(MAXERR),SMVOLT(MAXERR)
60     FORMAT ( 1H , 20X, F6.2, 2X, 7HBECOMES, F6.2)
      RWVOLT(MAXERR)=SMVOLT(MAXERR)
      GO TO 137
52     N=IDGSMH/2+1
C      CALCULATE DENSITY
      DO 59 I=N,MAX
59     CALDEN(I)=SLOPE*SMVOLT(I)+YCEPT
      IF (KVAL)999,134,307
307    J = N
135    L = J + 19
      WRITE (6, 132) (CALDEN (I), I = J, L)
```

DATAN440
DATAX441
DATAN445
DATAX450
DATAX455
DATAX460
DATAN465
DATAN615
DATAN616
DATAN620
DATAN470
DATAN980
DATAN480
DATAN485
DATAN490
DATAN495
DATAN500
DATAN505
DATAN510
DATAN515
DATAN520
DATAN525
DATAN530
DATAN535
DATAN540
DATAN545
DATAN550
DATAN555
DATAN560
DATAN565

DATAX570
DATAX571

DATAX572

DATAX573
DATAX574
DATAX575
DATAN570
DATAN575
DATAN580
DATAX590
DATAX595
DATAN585
DATAN600
DATAN635
DATAN610
DATAN625
DATAN630

DATAX631
DATAX632
DATAX633

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```
132 FORMAT (1H , 20F6.3)
    IF (MAX - J) 134, 134, 133
133 J = J + 20
    GO TO 135
134 MAX=MAX-1
    COMPUTE LOWER CUTOFF
    DO 63 I = N, IMAX
    DO 64 J= 1, MXSCH, 2
    K = I + J
    Q = J
    IF (CALDEN(K) - CALDEN(I) - Q*CRTSLP) 63, 64, 64
64 CONTINUE
    ILOWER = I
    GO TO 69
63 CONTINUE
    WRITE(6,65)
65 FORMAT(1H ,15HNO LOWER CUTOFF)
    GO TO 99
69 IF (ILOWER - N - 4) 66, 67, 67
66 WRITE(6,68)
68 FORMAT(1H ,29HSHOULD HAVE MORE LOWER VALUES)
    COMPUTE UPPER CUTOFF
67 DO 70 I = IMAX, MAX
    DO 71 J = 1, MXSCH, 2
    K = I + J
    Q = J
    IF (CALDEN(K) - CALDEN(I) - Q*CRTSLP) 71, 71, 70
71 CONTINUE
    IUPPER = I
    IF (MAX - IUPPER - 5) 72, 72, 84
70 CONTINUE
    WRITE(6,80)
80 FORMAT(1H ,24HCANNOT FIND UPPER CUTOFF)
    GO TO 99
72 WRITE(6,73)
73 FORMAT(1H ,29HSHOULD HAVE MORE UPPER POINTS)
    COMPUTE GX2(AVF.)
84 SRATIO=0.
    DO 61 I=N,MAX
61 CALDEN(I)=CALDEN(I+1)-CALDEN(I)
    DO 89 I=ILOWER,IUPPER
89 SRATIO=SRATIO+1000.*CALDEN(I)*1000.*CALDEN(I)/(DELTX*DELTX)
    DMAX=SMVOLT(IUPPER)*SLOPE+YCEPT
    DMIN=SMVOLT(ILOWER)*SLOPE+YCEPT
    TEST = IUPPER - ILOWER
    ITEST=TEST
    ANSWER = SRATIO / (TEST* (DMAX - DMIN))
    DS=DMAX-XFOG
    WRITE(6,91) IRUN, ANSWER, DS, DMAX, DMIN, IDGSMH, IUPPER, ILOWER,
2 ITEST, MXNUM, TSTMX
91 FORMAT(1H ,13,2X,F9.1,2X,F6.2,3X,2(2X,F6.3),5(2X,I4), F8.3)
99 WRITE(6,98)
98 FORMAT(1H-)
    IRUN=IRUN+1
    GO TO 203
999 CALL EXIT
```

END

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DATAX634
DATAX635
DATAX636
DATAN655
DATAN670
DATAN675
DATAN680
DATAN685
DATAN686
DATAN687
DATAN695
DATAN700
DATAN705
DATAN685
DATAX690
DATAX695
DATAN700
DATAN710
DATAX715
DATAX720
DATAN815
DATAN820
DATAN825
DATAN830

DATAN840
DATAN845
DATAN850
DATAN860
DATAX840
DATAX845
DATAN850
DATAX865
DATAX870
DATAN920
DATAN925
DATAN660
DATAN665
DATAN935
DATAN940
DATAN945
DATAN950
DATAN955

DATAN956
DATAN960
DATAX965
DATAX966
DATAX970
DATAX982
DATAX983
DATAN985
DATAN986
DATAX
DATAN990

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***** SAMPLE -- TYPICAL INPUT DATA *****

0.95 0.30

0.0250 80.

SPITZ 15B AND 26B 0.02

145 002
240 032
342 080
465 120
637 192
703 212
860 268
999

7 9

432	433	434	435	435	434	431	430	430	429	430	431	431	431	432	430	431	431	432	434
434	434	433	432	431	431	432	433	432	431	429	428	426	426	426	426	427	428	428	427
428	427	427	428	430	432	434	435	436	437	438	437	437	436	434	432	433	432	433	432
435	436	437	439	439	440	441	441	441	443	446	447	447	447	446	445	441	437	430	416
398	371	340	310	281	252	227	205	188	176	165	158	153	151	147	145	143	142	140	139
138	138	138	137	137	137	136	136	136	136	136	136	136	136	137	136	136	136	137	136
137	136	136	136	136	136	136	136	136	136	135	136	135	136	135	136	135	136	135	136

***** SAMPLE -- OUTPUT DATA *****

*** PRO-DIAGNO PROGRAM B.B. 29-J (DEC 7,1964)***

MIN. CORCO ALLOWED = 0.95 MAX. 4TH DIFF. ALLOWED = 0.30
RATE OF TRAVEL = 0.0250 SAMPLES PER MINUTE = 80.0
DELTX = 0.312
CRISLP = 0.00156

SPITZ 15B AND 26B 0.02
CORCC OF 0.999 OKAY

1 30565.7 1.15 1.166 0.001 7 59 32 27 132 0.120

SECRET

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